

# ATOMIC FORCE MICROSCOPY (AFM)

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MANUFACTURER : Digital Instruments Veeco

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MODEL : NanoMan VS

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## Samples

- Samples size : 150 mm maximum

## Analysis

- Modes: contact, non-contact, lateral force, phase image, magnetic force, electronic force, surface potential and torsion resonance
- Scanning range: 90  $\mu\text{m}$  (X-Y), 9  $\mu\text{m}$  (Z)
- Number of measurement points per image: 5120 x 5120
- Resolution : 16 bits
- Motorized stage: operating range 120 x 100 mm

## Applications

- Analysis of small surface phases
- Nanometric scale validation of photoresist final surfaces
- Surface analysis of hard materials

## Characteristics

- Unidirectional resolution: 2  $\mu\text{m}$
- Scanning speed and range adjustable
- Thickness: 12 mm maximum
- Z noise: less than 0.1 nm RMS
- Limitations: some semi-crystalline materials may be analyzed
- Incompatibility: all soft materials